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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	83
Number of Gates	24000
Voltage - Supply	3V ~ 3.6V, 4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	100-BQFP
Supplier Device Package	100-PQFP (20x14)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a42mx16-2pq100i

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- The Transient Current, page 13 is new (SAR 36930).
- Package names were revised according to standards established in *Package Mechanical Drawings* (SAR 34774)

1.7 Revision 9.0

The following is a summary of the changes in revision 9.0 of this document

- In Table 20, page 23, the limits in VI were changed from -0.5 to VCCI + 0.5 to -0.5 to VCCA + 0.5

In Table 22, page 25, V_{OH} was changed from 3.7 to 2.4 for the min in industrial and military. V_{IH} had V_{CCI} and that was changed to VCCA

1.8 Revision 6.0

The following is a summary of the changes in revision 6.0 of this document.

- The Ease of Integration, page 1 was updated
- The Temperature Grade Offerings, page 5 is new
- The Speed Grade Offerings, page 5 is new
- The General Description, page 6 was updated
- The MultiPlex I/O Modules, page 11 was updated
- The User Security, page 12 was updated
- Table 6, page 13 was updated
- The Power Dissipation, page 14 was updated.
- The Static Power Component, page 14 was updated
- The Equivalent Capacitance, page 15 was updated
- Figure 13, page 17 was updated
- Table 10, page 18 was updated.
- Figure 14, page 18 was updated.
- Table 11, page 19 was updated.

Figure 5 • **A42MX24 and A42MX36 D-Module Implementation**

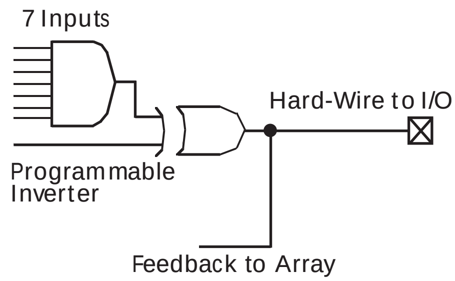
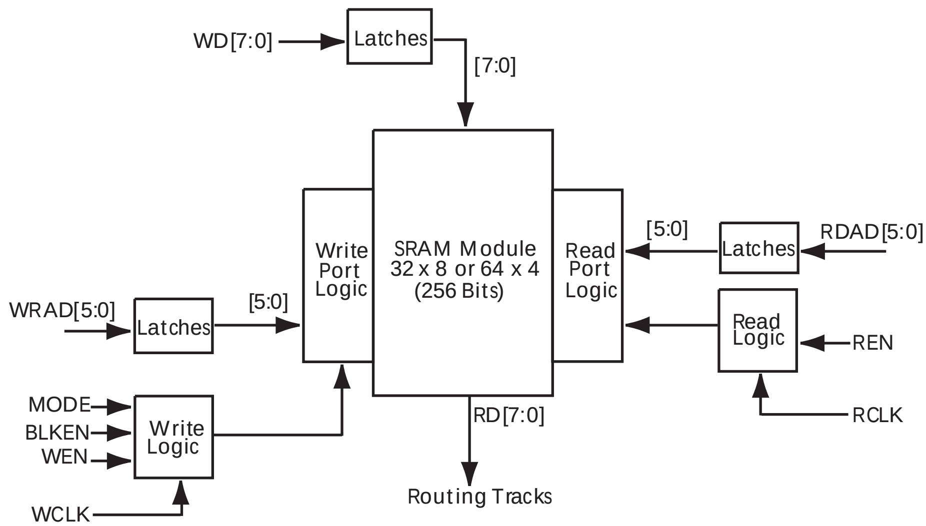


Figure 6 • **A42MX36 Dual-Port SRAM Block**



3.2.3 Routing Structure

The MX architecture uses vertical and horizontal routing tracks to interconnect the various logic and I/O modules. These routing tracks are metal interconnects that may be continuous or split into segments. Varying segment lengths allow the interconnect of over 90% of design tracks to occur with only two antifuse connections. Segments can be joined together at the ends using antifuses to increase their lengths up to the full length of the track. All interconnects can be accomplished with a maximum of four antifuses.

3.2.3.1 Horizontal Routing

Horizontal routing tracks span the whole row length or are divided into multiple segments and are located in between the rows of modules. Any segment that spans more than one-third of the row length is considered a long horizontal segment. A typical channel is shown in Figure 7, page 10. Within horizontal routing, dedicated routing tracks are used for global clock networks and for power and ground tie-off tracks. Non-dedicated tracks are used for signal nets.

3.2.3.2 Vertical Routing

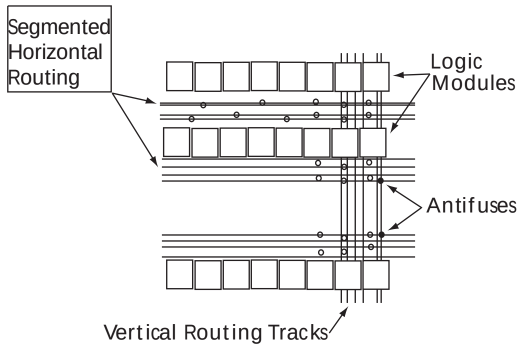
Another set of routing tracks run vertically through the module. There are three types of vertical tracks: input, output, and long. Long tracks span the column length of the module, and can be divided into multiple segments. Each segment in an input track is dedicated to the input of a particular module; each segment in an output track is dedicated to the output of a particular module. Long segments are uncommitted and can be assigned during routing.

Each output segment spans four channels (two above and two below), except near the top and bottom of the array, where edge effects occur. Long vertical tracks contain either one or two segments. An example of vertical routing tracks and segments is shown in Figure 7, page 10.

3.2.3.3 Antifuse Structures

An antifuse is a “normally open” structure. The use of antifuses to implement a programmable logic device results in highly testable structures as well as efficient programming algorithms. There are no pre-existing connections; temporary connections can be made using pass transistors. These temporary connections can isolate individual antifuses to be programmed and individual circuit structures to be tested, which can be done before and after programming. For instance, all metal tracks can be tested for continuity and shorts between adjacent tracks, and the functionality of all logic modules can be verified.

Figure 7 • **MX Routing Structure**



3.2.4 Clock Networks

The 40MX devices have one global clock distribution network (CLK). A signal can be put on the CLK network by being routed through the CLKBUF buffer.

In 42MX devices, there are two low-skew, high-fanout clock distribution networks, referred to as CLKA and CLKB. Each network has a clock module (CLKMOD) that can select the source of the clock signal from any of the following (Figure 8, page 11):

- Externally from the CLKA pad, using CLKBUF buffer
- Externally from the CLKB pad, using CLKBUF buffer
- Internally from the CLKINTA input, using CLKINT buffer
- Internally from the CLKINTB input, using CLKINT buffer

The clock modules are located in the top row of I/O modules. Clock drivers and a dedicated horizontal clock track are located in each horizontal routing channel.

Clock input pads in both 40MX and 42MX devices can also be used as normal I/Os, bypassing the clock networks.

The A42MX36 device has four additional register control resources, called quadrant clock networks (Figure 9, page 11). Each quadrant clock provides a local, high-fanout resource to the contiguous logic modules within its quadrant of the device. Quadrant clock signals can originate from specific I/O pins or from the internal array and can be used as a secondary register clock, register clear, or output enable.

f_{q2} = Average second routed array clock rate in MHz)

Table 7 • Fixed Capacitance Values for MX FPGAs (pF)

Device Type	r1 routed_Clk1	r2 routed_Clk2
A40MX02	41.4	N/A
A40MX04	68.6	N/A
A42MX09	118	118
A42MX16	165	165
A42MX24	185	185
A42MX36	220	220

3.4.6 Test Circuitry and Silicon Explorer II Probe

MX devices contain probing circuitry that provides built-in access to every node in a design, via the use of Silicon Explorer II. Silicon Explorer II is an integrated hardware and software solution that, in conjunction with the Designer software, allow users to examine any of the internal nets of the device while it is operating in a prototyping or a production system. The user can probe into an MX device without changing the placement and routing of the design and without using any additional resources. Silicon Explorer II's noninvasive method does not alter timing or loading effects, thus shortening the debug cycle and providing a true representation of the device under actual functional situations.

Silicon Explorer II samples data at 100 MHz (asynchronous) or 66 MHz (synchronous). Silicon Explorer II attaches to a PC's standard COM port, turning the PC into a fully functional 18-channel logic analyzer. Silicon Explorer II allows designers to complete the design verification process at their desks and reduces verification time from several hours per cycle to a few seconds.

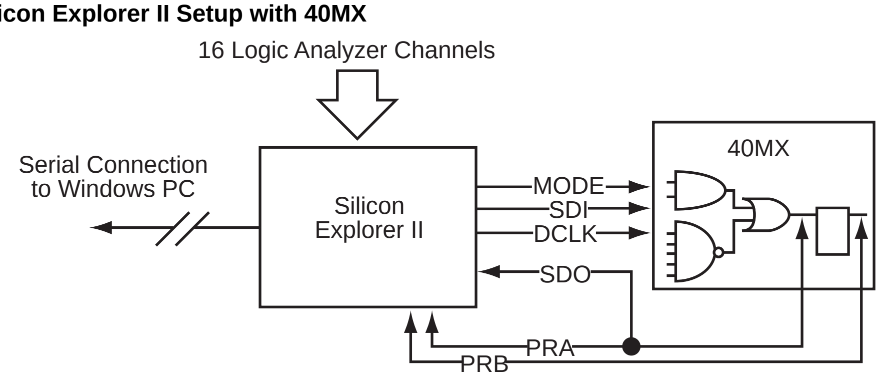
Silicon Explorer II is used to control the MODE, DCLK, SDI and SDO pins in MX devices to select the desired nets for debugging. The user simply assigns the selected internal nets in the Silicon Explorer II software to the PRA/PRB output pins for observation. Probing functionality is activated when the MODE pin is held HIGH.

Figure 12, page 16 illustrates the interconnection between Silicon Explorer II and 40MX devices, while Figure 13, page 17 illustrates the interconnection between Silicon Explorer II and 42MX devices

To allow for probing capabilities, the security fuses must not be programmed. (See User Security, page 12 for the security fuses of 40MX and 42MX devices). Table 8, page 17 summarizes the possible device configurations for probing.

PRA and PRB pins are dual-purpose pins. When the “Reserve Probe Pin” is checked in the Designer software, PRA and PRB pins are reserved as dedicated outputs for probing. If PRA and PRB pins are required as user I/Os to achieve successful layout and “Reserve Probe Pin” is checked, the layout tool will override the option and place user I/Os on PRA and PRB pins.

Figure 12 • Silicon Explorer II Setup with 40MX



Each I/O cell has three boundary-scan register cells, each with a serial-in, serial-out, parallel-in, and parallel-out pin. The serial pins are used to serially connect all the boundary-scan register cells in a device into a boundary-scan register chain, which starts at the TDI pin and ends at the TDO pin. The parallel ports are connected to the internal core logic tile and the input, output and control ports of an I/O buffer to capture and load data into the register to control or observe the logic state of each I/O.

Figure 14 • **42MX IEEE 1149.1 Boundary Scan Circuitry**

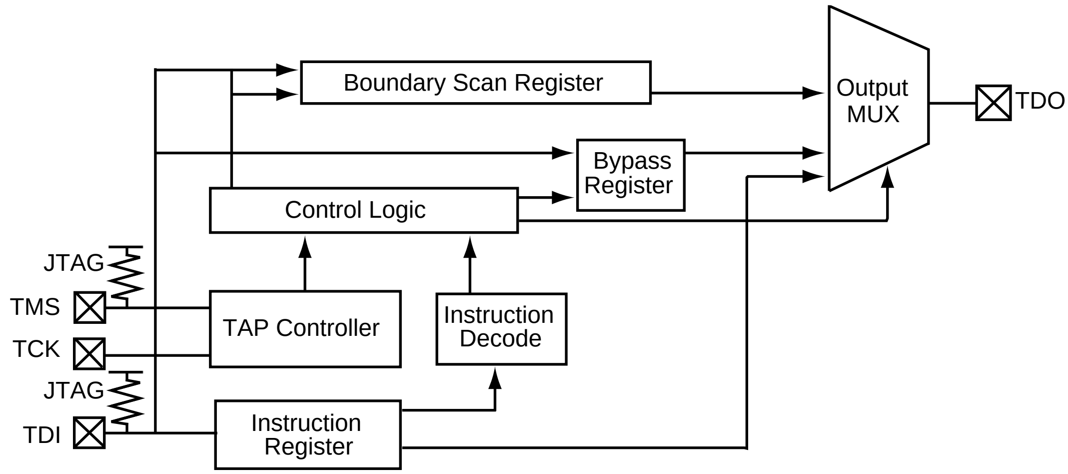


Table 9 • **Test Access Port Descriptions**

Port	Description
TMS (Test Mode Select)	Serial input for the test logic control bits. Data is captured on the rising edge of the test logic clock (TCK).
TCK (Test Clock Input)	Dedicated test logic clock used serially to shift test instruction, test data, and control inputs on the rising edge of the clock, and serially to shift the output data on the falling edge of the clock. The maximum clock frequency for TCK is 20 MHz.
TDI (Test Data Input)	Serial input for instruction and test data. Data is captured on the rising edge of the test logic clock.
TDO (Test Data Output)	Serial output for test instruction and data from the test logic. TDO is set to an Inactive Drive state (high impedance) when data scanning is not in progress.

Table 10 • **Supported BST Public Instructions**

Instruction	IR Code (IR2.IR0)	Instruction Type	Description
EXTEST	000	Mandatory	Allows the external circuitry and board-level interconnections to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
SAMPLE/PRELOAD	001	Mandatory	Allows a snapshot of the signals at the device pins to be captured and examined during operation
HIGH Z	101	Optional	Tristates all I/Os to allow external signals to drive pins. See the IEEE Standard 1149.1 specification.
CLAMP	110	Optional	Allows state of signals driven from component pins to be determined from the Boundary-Scan Register. See the IEEE Standard 1149.1 specification for details.
BYPASS	111	Mandatory	Enables the bypass register between the TDI and TDO pins. The test data passes through the selected device to adjacent devices in the test chain.

3.8.1 3.3 V LVTTL Electrical Specifications

Table 19 • **3.3V LVTTL Electrical Specifications**

		Commercial		Commercial -F		Industrial		Military		
Symbol	**Parameter**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
VOH[1]	IOH = –4 mA	2.15		2.15		2.4		2.4		V
VOL[1]	IOL = 6 mA		0.4		0.4		0.48		0.48	V
VIL		–0.3	0.8	–0.3	0.8	–0.3	0.8	–0.3	0.8	V
VIH (40MX)		2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	V
VIH (42MX)		2.0	VCCI + 0.3	2.0	VCCI + 0.3	2.0	VCCI + 0.3	2.0	VCCI + 0.3	V
IIL			–10		–10		–10		–10	µA
IIH			–10		–10		–10		–10	µA
Input Transition Time, T_R and T_F			500		500		500		500	ns
C_{IO} I/O Capacitance			10		10		10		10	pF
Standby Current, ICC[2]	A40MX02, A40MX04		3		25		10		25	mA
	A42MX09		5		25		25		25	mA
	A42MX16		6		25		25		25	mA
	A42MX24, A42MX36		15		25		25		25	mA
Low-Power Mode Standby Current	42MX devices only		0.5		ICC - 5.0		ICC - 5.0		ICC - 5.0	mA
IIO, I/O source sink current	Can be derived from the *IBIS model* (http://www.microsemi.com/soc/techdocs/models/ibis.html)									

1. Only one output tested at a time. VCC/VCCI = min.
2. All outputs unloaded. All inputs = VCC/VCCI or GND.

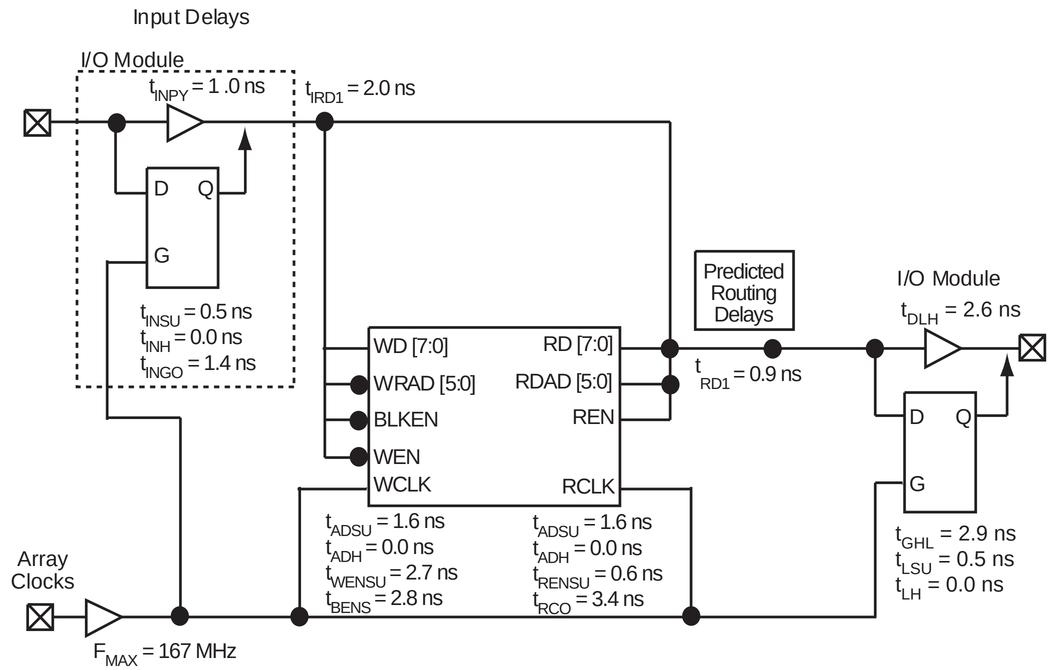
3.9 Mixed 5.0 V / 3.3 V Operating Conditions (for 42MX Devices Only)

Table 20 • **Absolute Maximum Ratings***

Symbol	Parameter	Limits	Units
VCCI	DC Supply Voltage for I/Os	–0.5 to +7.0	V
VCCA	DC Supply Voltage for Array	–0.5 to +7.0	V
VI	Input Voltage	–0.5 to VCCA +0.5	V
VO	Output Voltage	–0.5 to VCCI + 0.5	V
t_{STG}	Storage Temperature	–65 to +150	°C

Note: *Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device

Figure 20 • **42MX Timing Model (SRAM Functions)**



Note: Values are shown for A42MX36 –3 at 5.0 V worst-case commercial conditions.

3.10.1 Parameter Measurement

The following figures show parameter measurement details.

Figure 21 • **Output Buffer Delays**

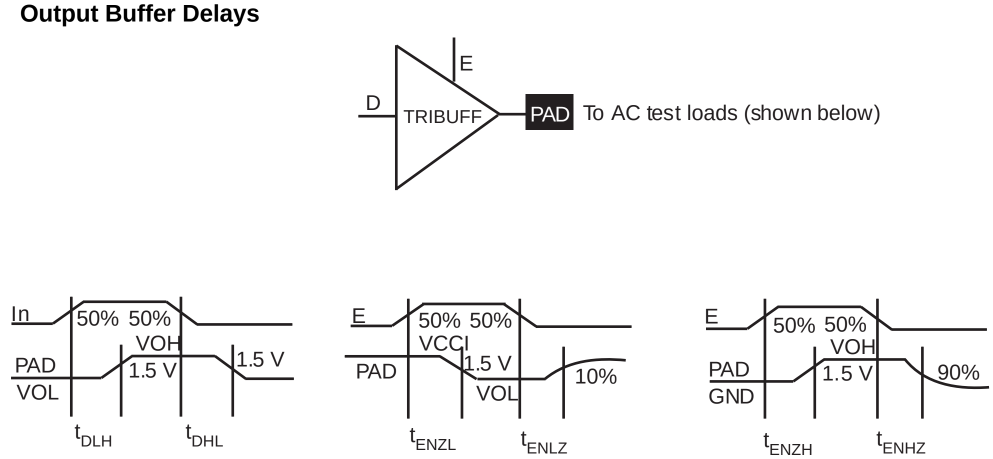
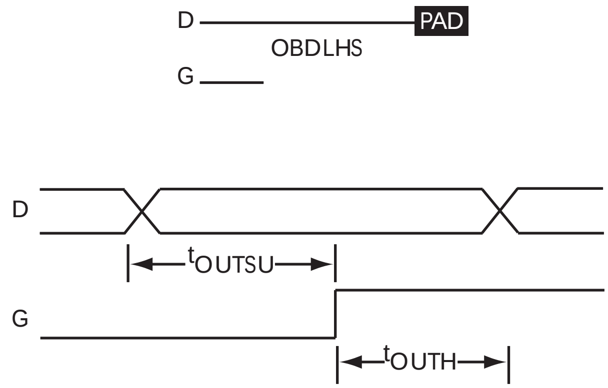


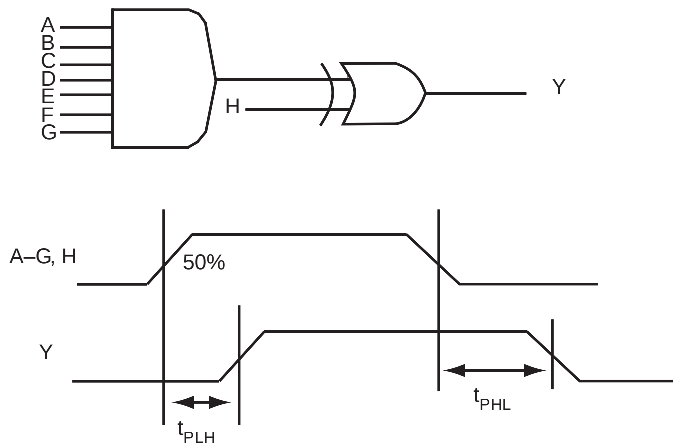
Figure 27 • **Output Buffer Latches**



3.10.4 Decode Module Timing

The following figure shows decode module timing.

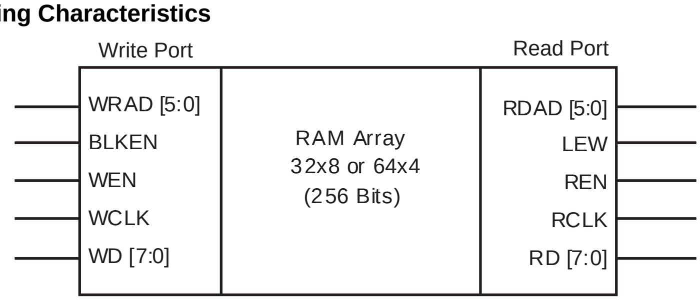
Figure 28 • **Decode Module Timing**



3.10.5 SRAM Timing Characteristics

The following figure shows SRAM timing characteristics.

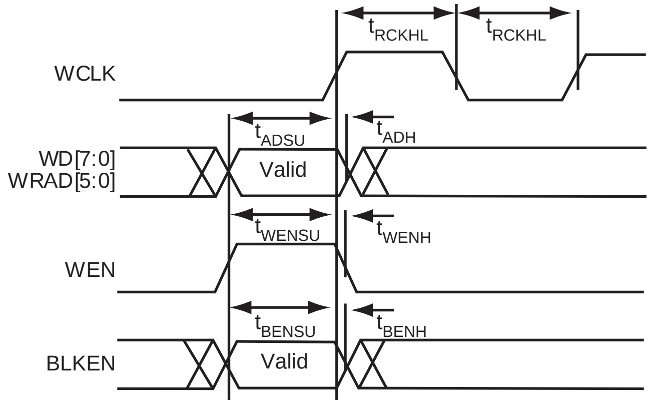
Figure 29 • **SRAM Timing Characteristics**



3.10.6 Dual-Port SRAM Timing Waveforms

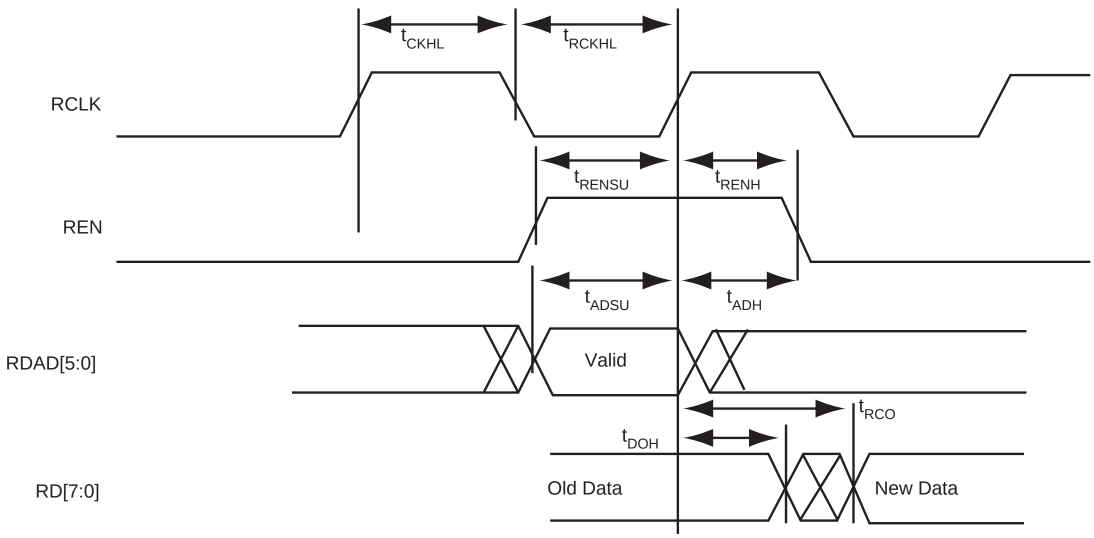
The following figures show dual-port SRAM timing waveforms.

Figure 30 • **42MX SRAM Write Operation**



Note: Identical timing for falling edge clock

Figure 31 • **42MX SRAM Synchronous Read Operation**



Note: Identical timing for falling edge clock

Figure 32 • **42MX SRAM Asynchronous Read Operation—Type 1 (Read Address Controlled)**

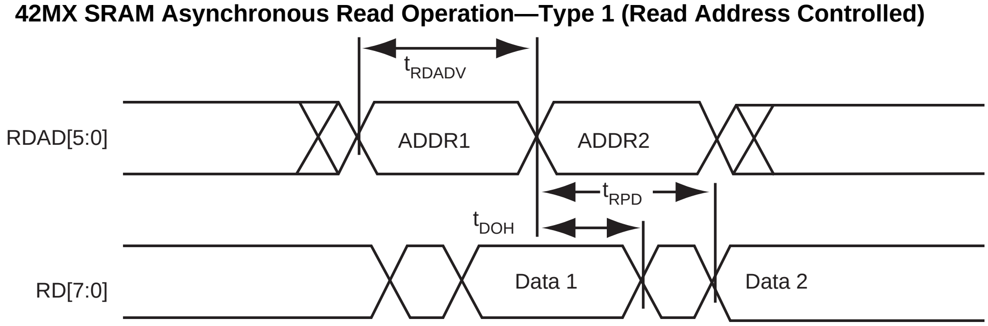


Table 36 • **A40MX04 Timing Characteristics (Nominal 5.0 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C)**

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
t_{HENA}	Flip-Flop (Latch) Enable Hold		0.0		0.0		0.0		0.0		0.0		ns
t_{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width		3.3		3.8		4.3		5.0		7.0		ns
t_{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width		3.3		3.8		4.3		5.0		7.0		ns
t_A	Flip-Flop Clock Input Period		4.8		5.6		6.3		7.5		10.4		ns
f_{MAX}	Flip-Flop (Latch) Clock Frequency (FO = 128)			181		167		154		134		80	MHz
Input Module Propagation Delays													
t_{INYH}	Pad-to-Y HIGH			0.7		0.8		0.9		1.1		1.5	ns
t_{INYL}	Pad-to-Y LOW			0.6		0.7		0.8		1.0		1.3	ns
Input Module Predicted Routing Delays[1]													
t_{IRD1}	FO = 1 Routing Delay			2.1		2.4		2.2		3.2		4.5	ns
t_{IRD2}	FO = 2 Routing Delay			2.6		3.0		3.4		4.0		5.6	ns
t_{IRD3}	FO = 3 Routing Delay			3.1		3.6		4.1		4.8		6.7	ns
t_{IRD4}	FO = 4 Routing Delay			3.6		4.2		4.8		5.6		7.8	ns
t_{IRD8}	FO = 8 Routing Delay			5.7		6.6		7.5		8.8		12.4	ns
Global Clock Network													
t_{CKH}	Input Low to HIGH	FO = 16 FO = 128		4.6 4.6		5.3 5.3		6.0 6.0		7.0 7.0		9.8 9.8	ns
t_{CKL}	Input High to LOW	FO = 16 FO = 128		4.8 4.8		5.6 5.6		6.3 6.3		7.4 7.4		10.4 10.4	ns
t_{PWH}	Minimum Pulse Width HIGH	FO = 16 FO = 128	2.2 2.4		2.6 2.7		2.9 3.1		3.4 3.6		4.8 5.1		ns
t_{PWL}	Minimum Pulse Width LOW	FO = 16 FO = 128	2.2 2.4		2.6 2.7		2.9 3.01		3.4 3.6		4.8 5.1		ns
t_{CKSW}	Maximum Skew	FO = 16 FO = 128		0.4 0.5		0.5 0.6		0.5 0.7		0.6 0.8		0.8 1.2	ns
t_P	Minimum Period	FO = 16 FO = 128	4.7 4.8		5.4 5.6		6.1 6.3		7.2 7.5		10.0 10.4		ns
f_{MAX}	Maximum Frequency	FO = 16 FO = 128		188 181		175 168		160 154		139 134		83 80	MHz
TTL Output Module Timing[4]													
t_{DLH}	Data-to-Pad HIGH			3.3		3.8		4.3		5.1		7.2	ns
t_{DHL}	Data-to-Pad LOW			4.0		4.6		5.2		6.1		8.6	ns
t_{ENZH}	Enable Pad Z to HIGH			3.7		4.3		4.9		5.8		8.0	ns
t_{ENZL}	Enable Pad Z to LOW			4.7		5.4		6.1		7.2		10.1	ns
t_{ENHZ}	Enable Pad HIGH to Z			7.9		9.1		10.4		12.2		17.1	ns

Table 40 • **A42MX16 Timing Characteristics (Nominal 5.0 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)**

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
t_{PWL}	Minimum Pulse Width LOW	FO = 32	3.2		3.5		4.0		4.7		6.6		ns
		FO = 384	3.7		4.1		4.6		5.4		7.6		ns
t_{CKSW}	Maximum Skew	FO = 32		0.3		0.4		0.4		0.5		0.7	ns
		FO = 384		0.3		0.4		0.4		0.5		0.7	ns
t_{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0		ns
		FO = 384	0.0		0.0		0.0		0.0		0.0		ns
t_{HEXT}	Input Latch External Hold	FO = 32	2.8		3.1		5.5		4.1		5.7		ns
		FO = 384	3.2		3.5		4.0		4.7		6.6		ns
t_P	Minimum Period	FO = 32	4.2		4.67		5.1		5.8		9.7		ns
		FO = 384	4.6		5.1		5.6		6.4		10.7		ns
f_{MAX}	Maximum Frequency	FO = 32		237		215		198		172		103	MHz
		FO = 384		215		195		179		156		94	MHz

Table 41 • A42MX16 Timing Characteristics (Nominal 3.3 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Logic Module Sequential Timing[3, 4]													
t_{SUD}	Flip-Flop (Latch) Data Input Set-Up		0.5		0.5		0.6		0.7		0.9		ns
t_{HD}	Flip-Flop (Latch) Data Input Hold		0.0		0.0		0.0		0.0		0.0		ns
t_{SUENA}	Flip-Flop (Latch) Enable Set-Up		1.0		1.1		1.2		1.4		2.0		ns
t_{HENA}	Flip-Flop (Latch) Enable Hold		0.0		0.0		0.0		0.0		0.0		ns
t_{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width		4.8		5.3		6.0		7.1		9.9		ns
t_{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width		6.2		6.9		7.9		9.2		12.9		ns
t_A	Flip-Flop Clock Input Period		9.5		10.6		12.0		14.1		19.8		ns
t_{INH}	Input Buffer Latch Hold		0.0		0.0		0.0		0.0		0.0		ns
t_{INSU}	Input Buffer Latch Set-Up		0.7		0.8		0.9		1.01		1.4		ns
t_{OUTH}	Output Buffer Latch Hold		0.0		0.0		0.0		0.0		0.0		ns
t_{OUTSU}	Output Buffer Latch Set-Up		0.7		0.8		0.89		1.01		1.4		ns
f_{MAX}	Flip-Flop (Latch) Clock Frequency			129		117		108		94		56	MHz
Input Module Propagation Delays													
t_{INYH}	Pad-to-Y HIGH			1.5		1.6		1.9		2.2		3.1	ns
t_{INYL}	Pad-to-Y LOW			1.1		1.3		1.4		1.7		2.4	ns
t_{INGH}	G to Y HIGH			2.0		2.2		2.5		2.9		4.1	ns
t_{INGL}	G to Y LOW			2.0		2.2		2.5		2.9		4.1	ns
Input Module Predicted Routing Delays[2]													
t_{IRD1}	FO = 1 Routing Delay			2.6		2.9		3.2		3.8		5.3	ns
t_{IRD2}	FO = 2 Routing Delay			2.9		3.2		3.7		4.3		6.1	ns
t_{IRD3}	FO = 3 Routing Delay			3.3		3.6		4.1		4.9		6.8	ns
t_{IRD4}	FO = 4 Routing Delay			3.6		4.0		4.6		5.4		7.6	ns
t_{IRD8}	FO = 8 Routing Delay			5.1		5.6		6.4		7.5		10.5	ns
Global Clock Network													
t_{CKH}	Input LOW to HIGH	FO = 32 FO = 384		4.4 4.8		4.8 5.3		5.5 6.0		6.5 7.1		9.0 9.9	ns ns
t_{CKL}	Input HIGH to LOW	FO = 32 FO = 384		5.3 6.2		5.9 6.9		6.7 7.9		7.8 9.2		11.0 12.9	ns ns
t_{PWH}	Minimum Pulse Width HIGH	FO = 32 FO = 384	5.7 6.6		6.3 7.4		7.1 8.3		8.4 9.8		11.8 13.7		ns ns

Table 54 • PQ240

PQ240	
Pin Number	**A42MX36 Function**
237	GND
238	MODE
239	VCCA
240	GND

Figure 46 • **VQ80**

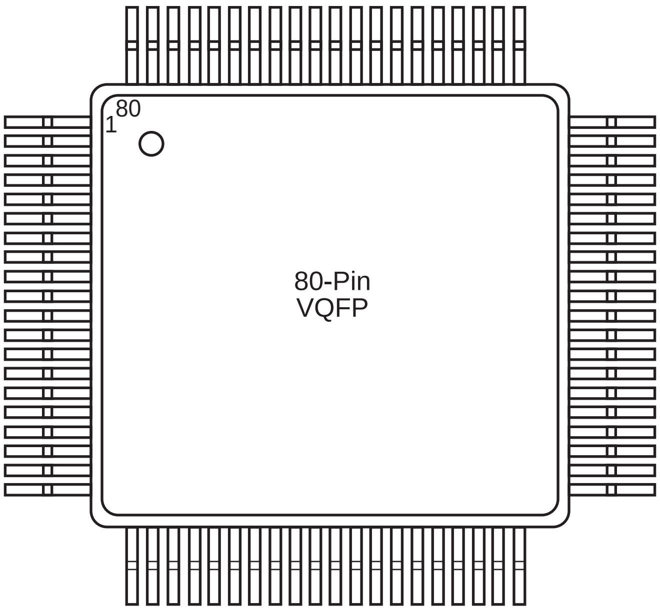


Table 55 • **VQ80**

VQ80		
Pin Number	**A40MX02 Function**	**A40MX04 Function**
1	I/O	I/O
2	NC	I/O
3	NC	I/O
4	NC	I/O
5	I/O	I/O
6	I/O	I/O
7	GND	GND
8	I/O	I/O
9	I/O	I/O
10	I/O	I/O
11	I/O	I/O
12	I/O	I/O

Figure 47 • **VQ100**

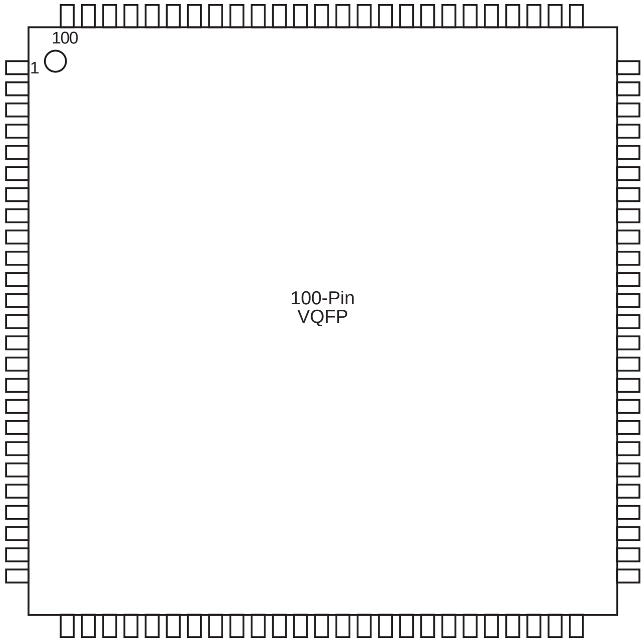


Table 56 • **VQ100**

VQ100		
Pin Number	**A42MX09 Function**	**A42MX16 Function**
1	I/O	I/O
2	MODE	MODE
3	I/O	I/O
4	I/O	I/O
5	I/O	I/O
6	I/O	I/O
7	GND	GND
8	I/O	I/O
9	I/O	I/O
10	I/O	I/O
11	I/O	I/O
12	I/O	I/O
13	I/O	I/O
14	VCCA	NC
15	VCCI	VCCI
16	I/O	I/O
17	I/O	I/O
18	I/O	I/O
19	I/O	I/O
20	GND	GND

Table 57 • **TQ176**

TQ176			
Pin Number	**A42MX09 Function**	**A42MX16 Function**	**A42MX24 Function**
158	CLKB, I/O	CLKB, I/O	CLKB, I/O
159	I/O	I/O	I/O
160	PRB, I/O	PRB, I/O	PRB, I/O
161	NC	I/O	WD, I/O
162	I/O	I/O	WD, I/O
163	I/O	I/O	I/O
164	I/O	I/O	I/O
165	NC	NC	WD, I/O
166	NC	I/O	WD, I/O
167	I/O	I/O	I/O
168	NC	I/O	I/O
169	I/O	I/O	I/O
170	NC	VCCI	VCCI
171	I/O	I/O	WD, I/O
172	I/O	I/O	WD, I/O
173	NC	I/O	I/O
174	I/O	I/O	I/O
175	DCLK, I/O	DCLK, I/O	DCLK, I/O
176	I/O	I/O	I/O

Figure 49 • **CQ208**

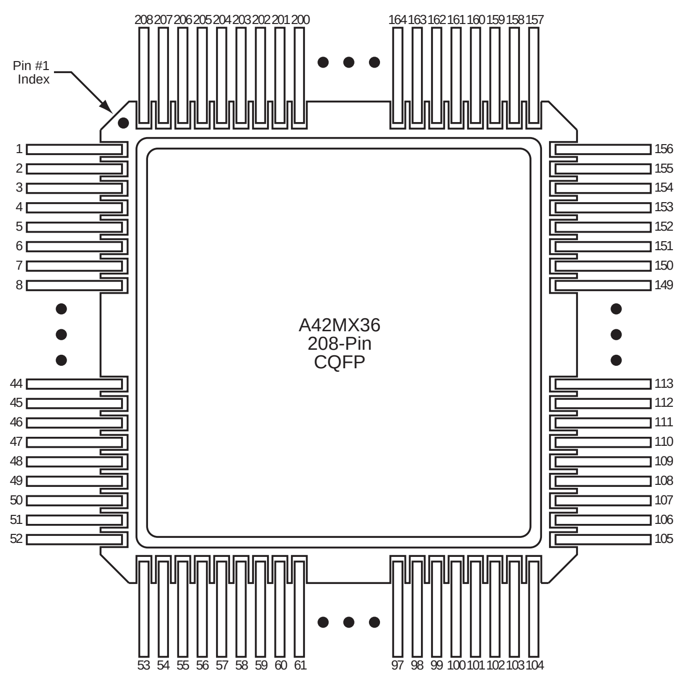


Table 59 • **CQ256**

CQ256	
Pin Number	**A42MX36 Function**
96	VCCA
97	GND
98	GND
99	I/O
100	I/O
101	I/O
102	I/O
103	I/O
104	I/O
105	WD, I/O
106	WD, I/O
107	I/O
108	I/O
109	WD, I/O
110	WD, I/O
111	I/O
112	QCLKA, I/O
113	I/O
114	GND
115	I/O
116	I/O
117	I/O
118	I/O
119	VCCI
120	I/O
121	WD, I/O
122	WD, I/O
123	I/O
124	I/O
125	I/O
126	I/O
127	GND
128	NC
129	NC
130	NC
131	GND
132	I/O

Table 61 • **PG132**

PG132	
Pin Number	**A42MX09 Function**
G12	VSV
F13	I/O
F12	I/O
F11	I/O
F10	I/O
E13	I/O
D13	I/O
D12	I/O
C13	I/O
B13	I/O
D11	I/O
C12	I/O
A13	I/O
C11	I/O
B12	SDI
B11	I/O
C10	I/O
A12	I/O
A11	I/O
B10	I/O
D8	I/O
A10	I/O
C8	I/O
A9	I/O
B8	PRBA
A8	I/O
B7	CLKA
A7	I/O
B6	CLKB
A6	I/O
C6	PRBB
A5	I/O
D6	I/O
A4	I/O
B4	I/O
A3	I/O
C4	I/O

Table 62 • **CQ172**

138	I/O
139	I/O
140	I/O
141	GND
142	I/O
143	I/O
144	I/O
145	I/O
146	I/O
147	I/O
148	PROBA
149	I/O
150	CLKA
151	VCC
152	GND
153	I/O
154	CLKB
155	I/O
156	PROBB
157	I/O
158	I/O
159	I/O
160	I/O
161	GND
162	I/O
163	I/O
164	I/O
165	I/O
166	VCCI
167	I/O
168	I/O
169	I/O
170	I/O
171	DCLK